United States Patent [19]

Gross

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[54] **ELECTRONIC TEST PROBE**

[75] Inventor: **Robert F. Gross**, Andover, Mass.

[73] Assignee: **Q.A. Technology Company**, Exeter, N.H.

[**] Term: **14 Years**

[21] Appl. No.: **101,169**

[22] Filed: **Sep. 25, 1987**

[52] **U.S. Cl.** **D10/80**

[58] **Field of Search** .... D10/75-80; 324/158 P

[56] **References Cited**

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[57] **CLAIM**

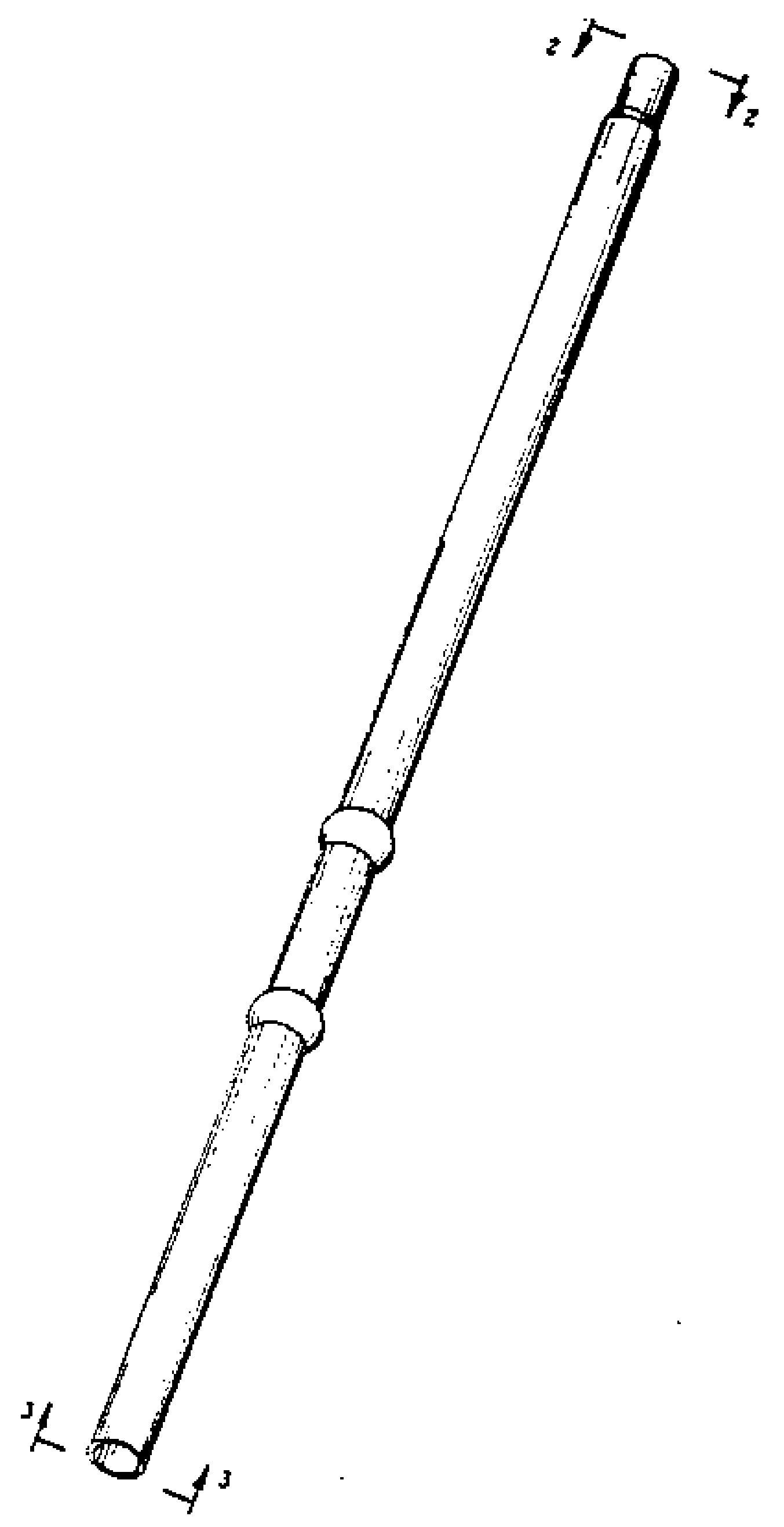
The ornamental design for electronic test probe, as shown and described.

DESCRIPTION

FIG. **1** is a front perspective view of a electronic test probe showing my new design;

FIG. **2** is a rear elevational view, taken along line **2—2** of FIG. **1**; and

FIG. **3** is a front end elevational view thereof, taken along line **3—3** of FIG. **3**.



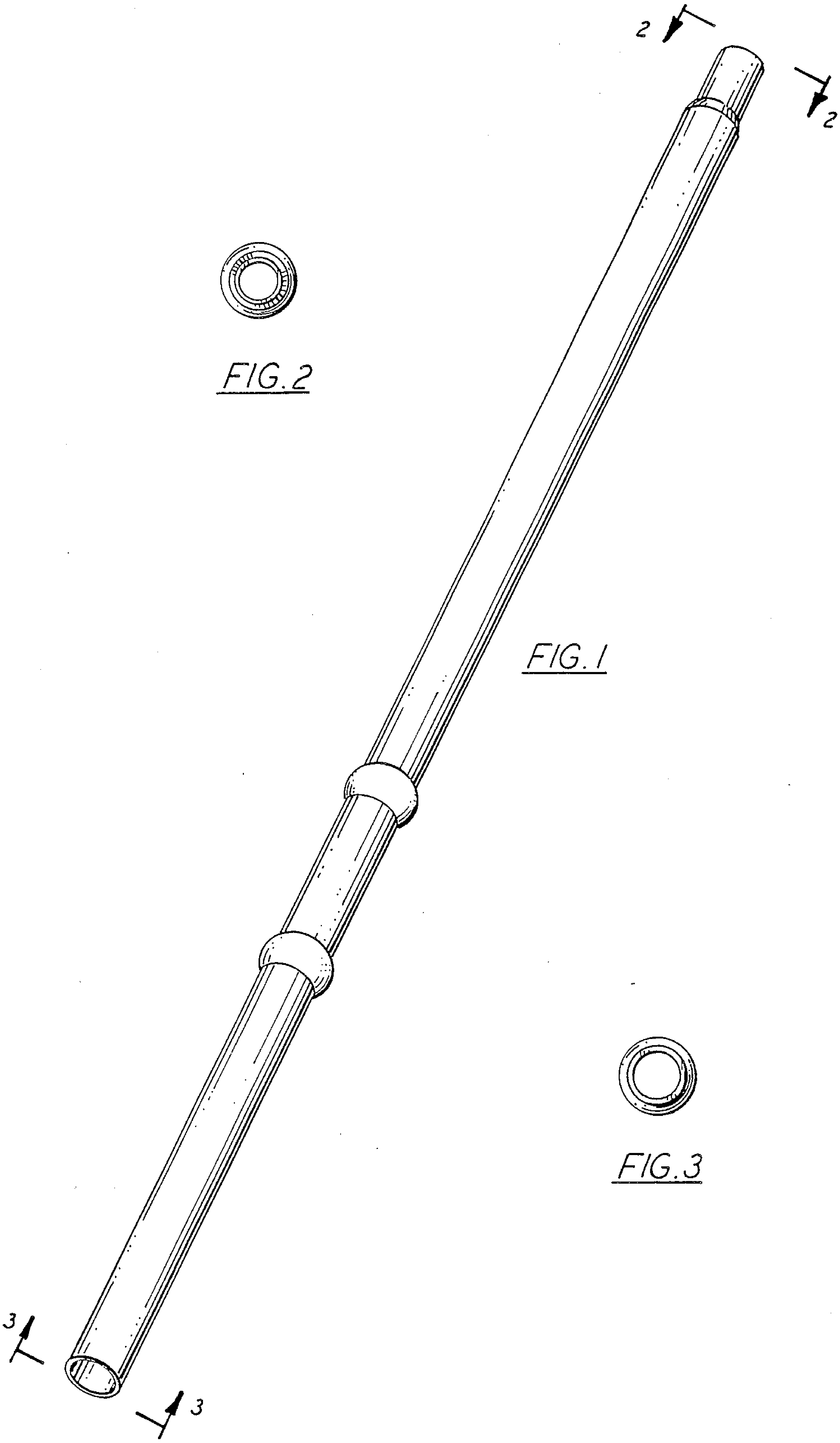


FIG. 2

FIG. 1

FIG. 3